
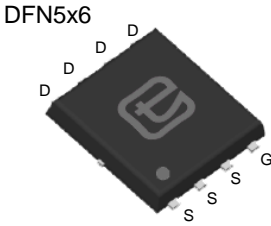
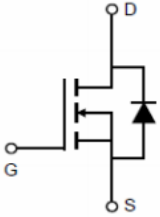




30V N-Channel Trench MOSFET(Preliminary)

<p>Features</p> <ul style="list-style-type: none"> ● Trench Power Technology ● Low $R_{DS(ON)}$ ● Low Gate Charge ● Optimized for Fast-switching Applications <p>Applications</p> <ul style="list-style-type: none"> ● Synchronous Rectification in DC/DC and AC/DC Converters ● Isolated DC/DC Converters in Telecom and Industrial 	<p>Product Summary</p> <p>V_{DS} 30V</p> <p>$R_{DS(ON)}$ (at V_{GS}=10V) < 2.2mΩ</p> <p>$R_{DS(ON)}$ (at V_{GS}=4.5V) < 3.0mΩ</p> <p>I_D (at V_{GS}=10V) 160A</p> <p>100% UIS Tested</p> 	
 		
Device	Package	Marking
TTG160N03GT	DFN5x6	160N03GT

Absolute Maximum Ratings T _C = 25°C, unless otherwise noted			
Parameter	Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)	V _{DSS}	30	V
Continuous Drain Current ^B	I _D	T _C = 25°C	51
		T _C = 100°C	51
Pulsed Drain Current ^A	I _{DM}	480	A
Gate-Source Voltage	V _{GSS}	±20	V
Single Pulse Avalanche Energy L = 0.3mH ^A	E _{AS}	277	mJ
Avalanche Current ^A	I _{AS}	43	A
Power Dissipation ^C	P _D	T _C = 25°C	143
		T _C = 100°C	71
Operating Junction and Storage Temperature Range	T _J , T _{SGT}	-55~+175	°C

Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R _{thJC}	1.1	°C/W
Thermal Resistance, Junction-to-Ambient	R _{thJA}	100	



Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30V, V_{GS} = 0V, T_J = 25^\circ\text{C}$	--	--	1	μA
		$V_{DS} = 30V, V_{GS} = 0V, T_J = 100^\circ\text{C}$	--	--	25	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20V$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.7	2.4	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 20A$	--	1.7	2.2	$m\Omega$
		$V_{GS} = 4.5V, I_D = 20A$	--	2.3	3.0	$m\Omega$
Forward Transconductance	g_{fs}	$V_{DS} = 10V, I_D = 20A$	34	--	--	S
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1.0\text{MHz}$	--	8313	--	pF
Output Capacitance	C_{oss}		--	951	--	
Reverse Transfer Capacitance	C_{rss}		--	897	--	
Total Gate Charge	Q_g	$V_{DD} = 15V, I_D = 50A, V_{GS} = 10V$	--	160	--	nC
Gate-Source Charge	Q_{gs}		--	18	--	
Gate-Drain Charge	Q_{gd}		--	34	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = 15V, I_D = 50A, R_G = 3\Omega$	--	27	--	ns
Turn-on Rise Time	t_r		--	25	--	
Turn-off Delay Time	$t_{d(off)}$		--	90	--	
Turn-off Fall Time	t_f		--	40	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current ^B	I_S	$T_C = 25^\circ\text{C}$	--	--	51	A
Pulsed Diode Forward Current ^B	I_{SM}		--	--	51	
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{SD} = 30A, V_{GS} = 0V$	--	--	1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 30A, di_F/dt = 100A/\mu s$	--	43	--	ns
Reverse Recovery Charge	Q_{rr}		--	40	--	nC

A. Single pulse width limited by maximum junction temperature.

B. The maximum current rating is package limited.

C. The power dissipation P_D is based on $T_{J(MAX)} = 175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.



Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 1. Output Characteristics

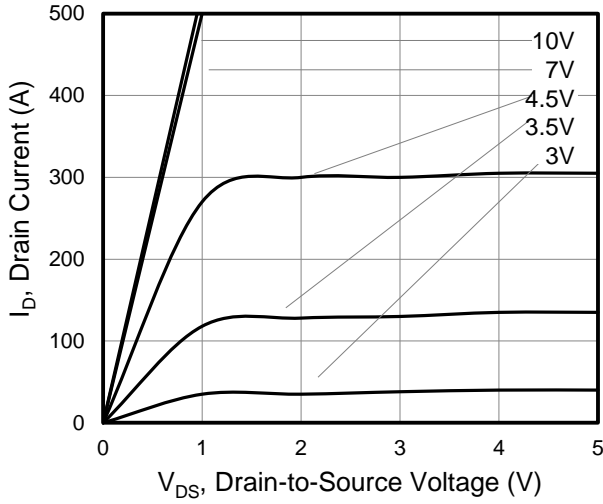


Figure 2. Transfer Characteristics

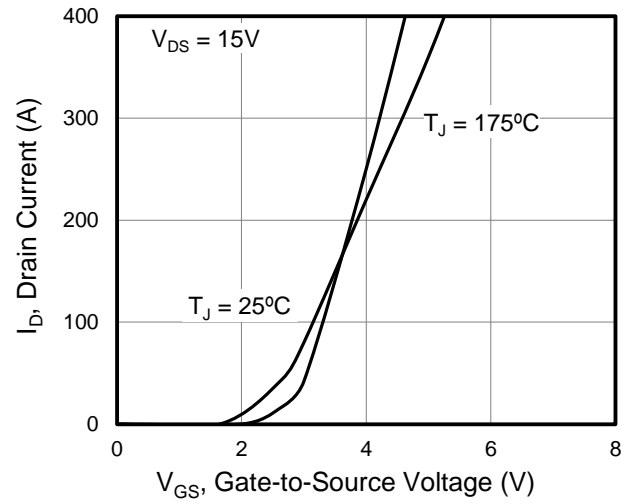


Figure 3. On-Resistance vs. Drain Current

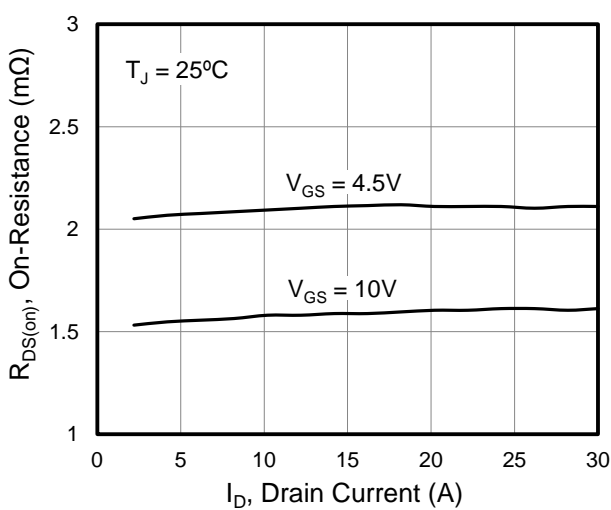


Figure 4. Capacitance

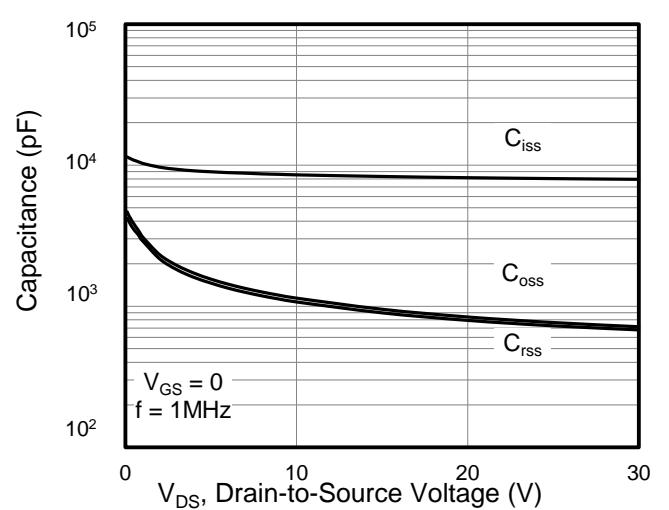


Figure 5. Gate Charge

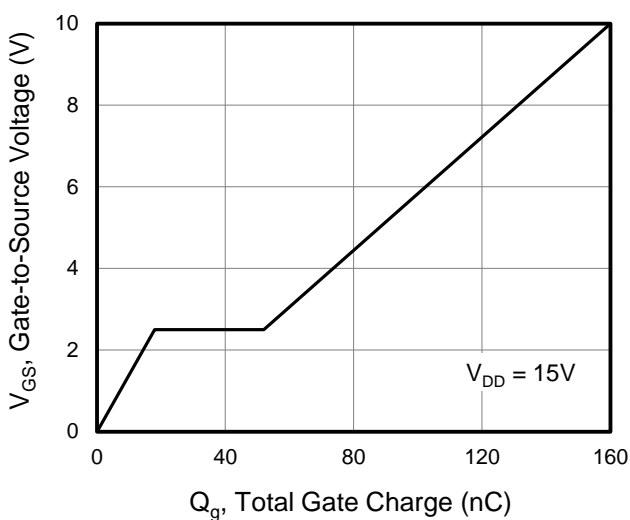
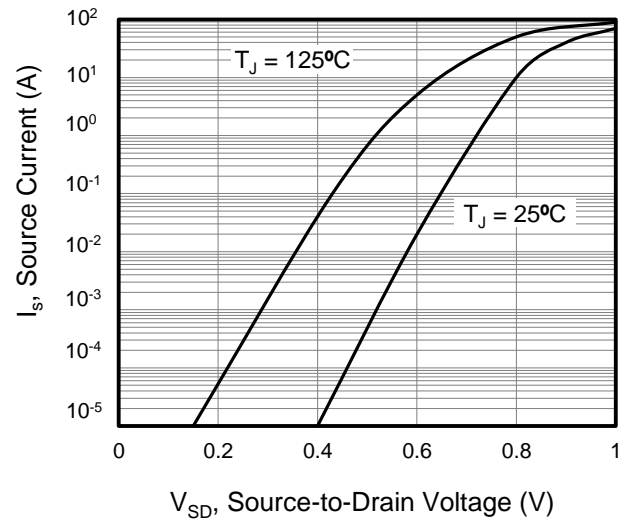


Figure 6. Body Diode Forward Voltage





Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted

Figure 7. On-Resistance vs. Junction Temperature

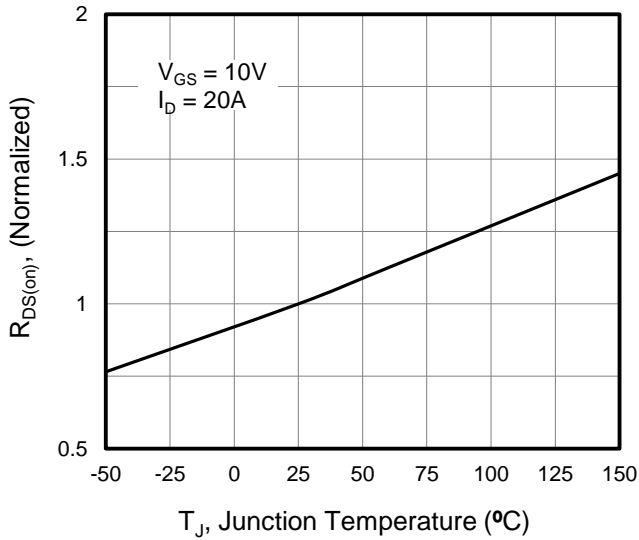


Figure 8. Threshold Voltage vs. Junction Temperature

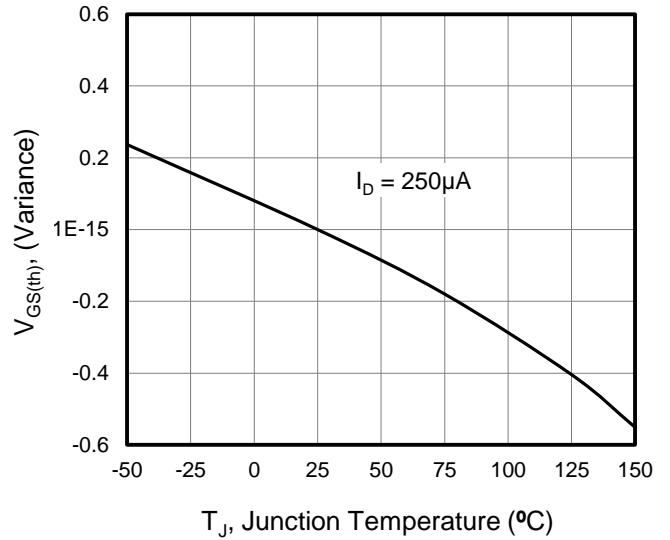


Figure 9. Transient Thermal Impedance

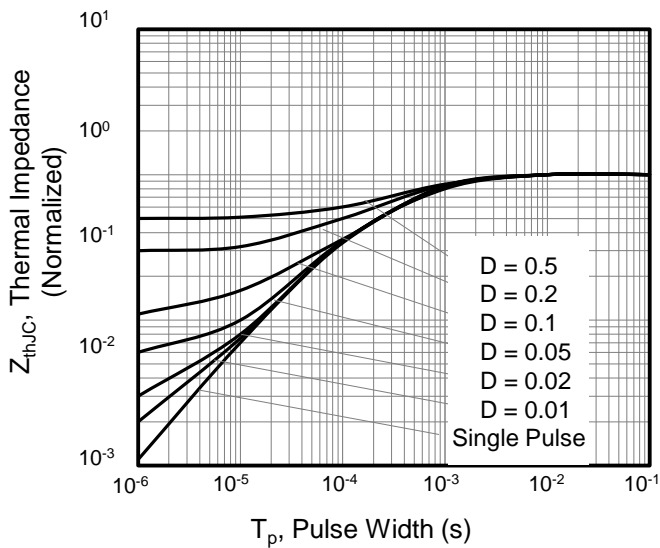


Figure 10. Safe operation area

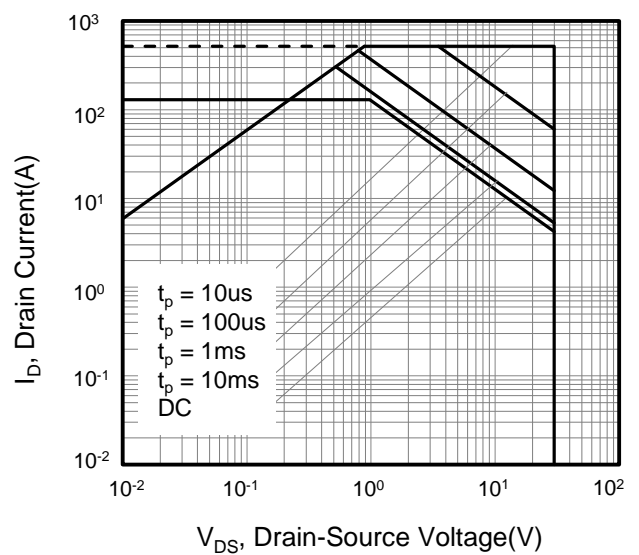




Figure A: Gate Charge Test Circuit and Waveform

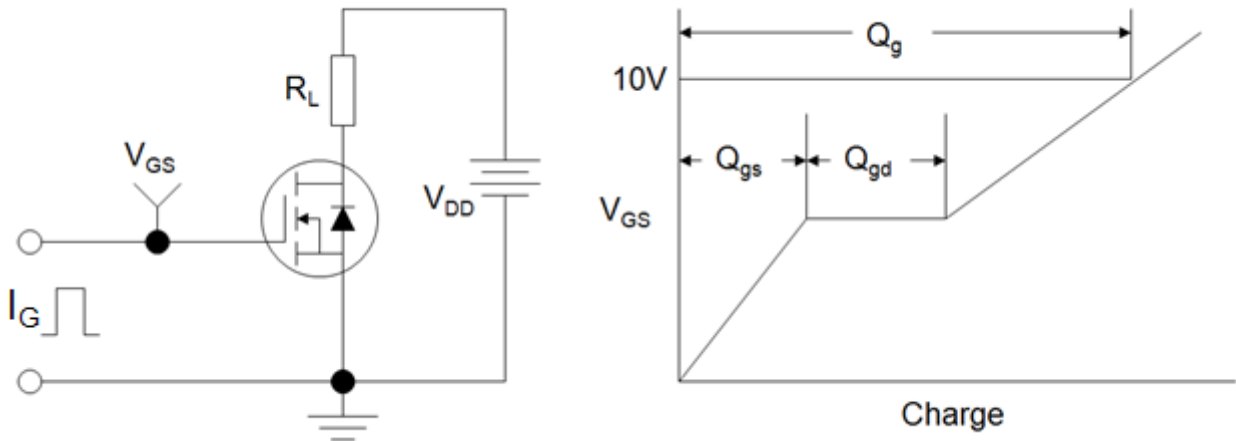


Figure B: Resistive Switching Test Circuit and Waveform

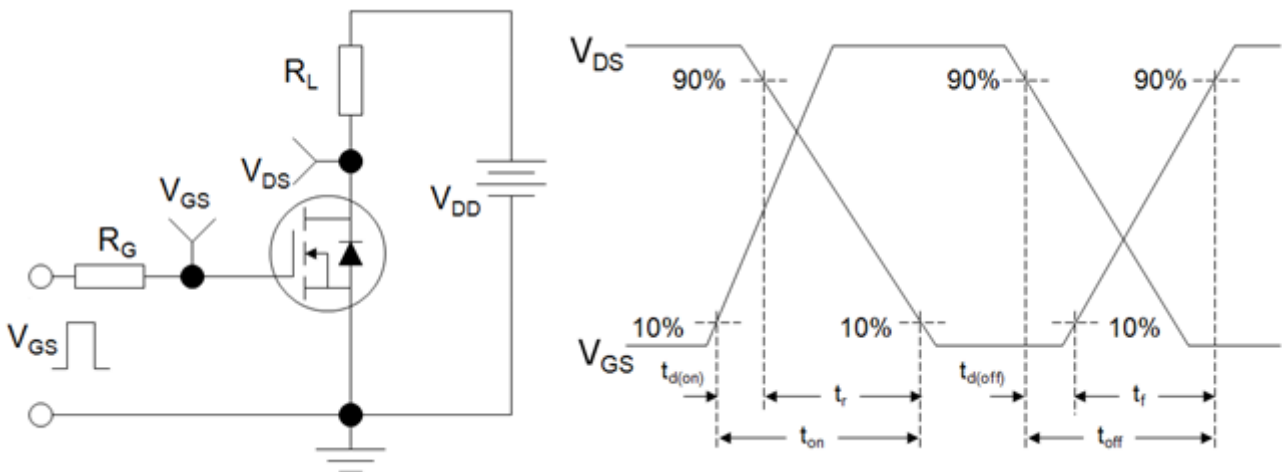
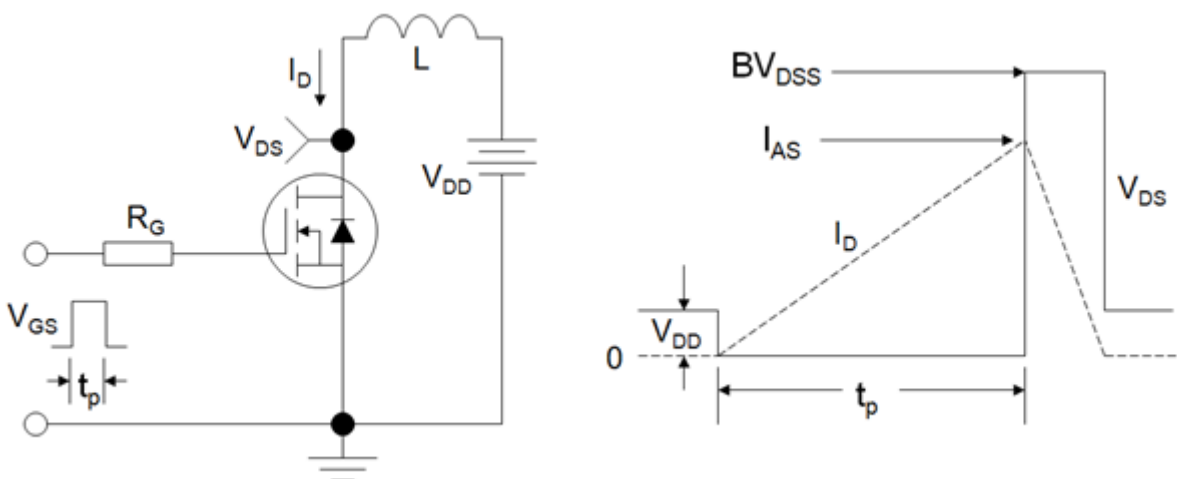
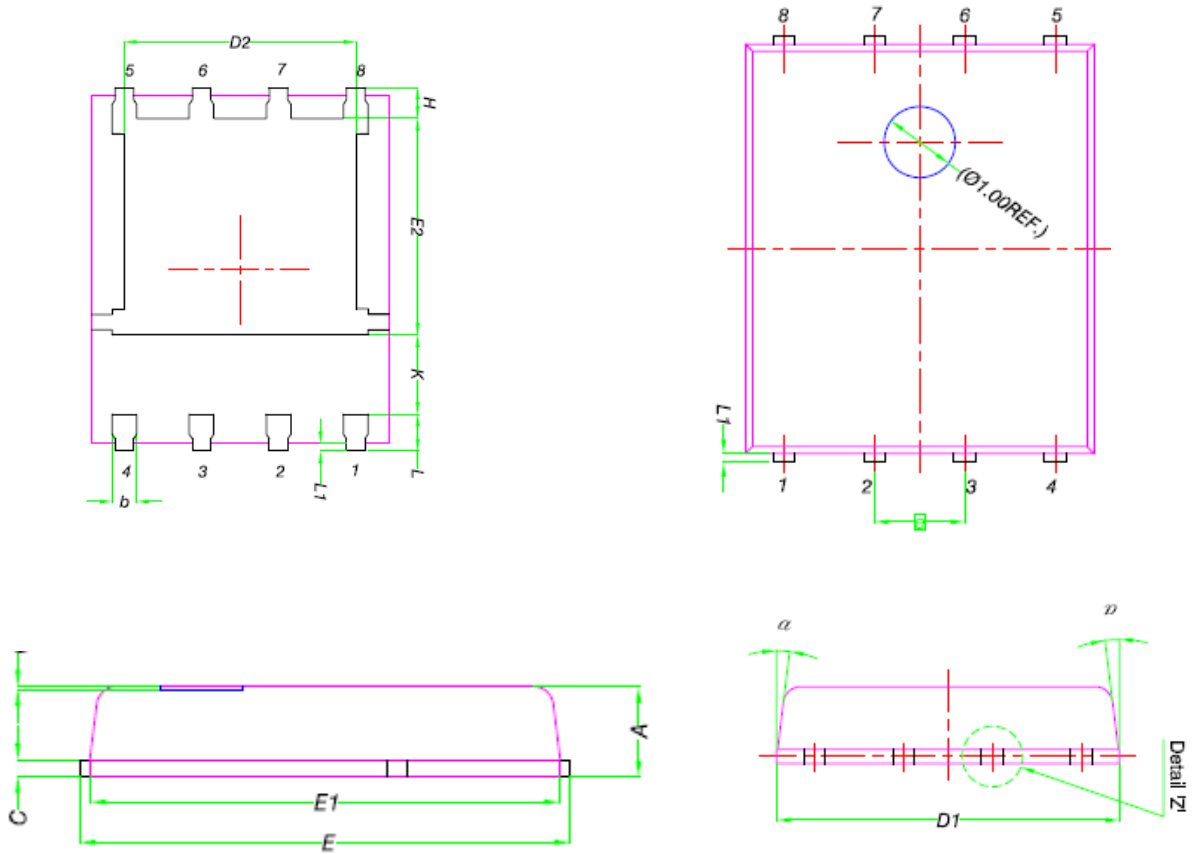


Figure C: Unclamped Inductive Switching Test Circuit and Waveform





DFN5x6



DIM.	MILLIMETERS			DIM.	MILLIMETERS		
	MIN.	NOM.	MAX.		MIN.	NOM.	MAX.
A	0.90	1.00	1.10	E	5.90	6.00	6.10
A1	0	-	0.05	E1	5.70	5.75	5.80
b	0.33	0.41	0.51	E2	3.38	3.58	3.78
C	0.20	0.25	0.30	e	1.27 BSC		
D1	4.80	4.90	5.00	H	0.41	0.51	0.61
D2	3.61	3.81	3.96	K	1.10	-	-
				L	0.51	0.61	0.71
				L1	0.06	0.13	0.20
				α	0°	-	12°



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